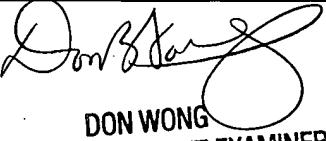


Issue Classification				Application/Control No.		Applicant(s)/Patent under Reexamination	
				10/750,368		LUCK ET AL.	
				Examiner		Art Unit	
				Binh V. Ho		2163	

ORIGINAL				CROSS REFERENCE(S)									
CLASS		SUBCLASS		CLASS		SUBCLASS (ONE SUBCLASS PER BLOCK)							
707		3		707		100	101	102	203				
INTERNATIONAL CLASSIFICATION													
G	0	6	F	17/30									
				/									
				/									
				/									
				/									
Binh Van Ho 12/21/2006 (Assistant Examiner) (Date)				 DON WONG ^{Primary Examiner} SUPERVISORY PATENT EXAMINER 12/26/06 ^(Legal Instruments Examiner) (Date) TECHNOLOGY CENTER 2100 (Date)								Total Claims Allowed: 6	
												O.G.	
				1		1		1		1			

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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